Search Notes

Аp	olication/Control N	lo.

Applicant(s)/Patent under Reexamination

MASUDA ET AL.
Art Unit

Examiner
Nam Huynh

10/758,227

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SEARCHED				
Class	Subclass	Date	Examiner	
See	Previous	8/2/2007	NTH	
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INTERFERENCE SEARCHED				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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See EAST search notes.	1/16/2008	NTH	